

**Search Notes**

Application/Control No.

10/760,456

Examiner

Ellen C. Tran

Applicant(s)/Patent under  
Reexamination

OHARA ET AL.

Art Unit

2134

**SEARCHED**

Class	Subclass	Date	Examiner
713	176	6/21/2007	ET
726	32	6/21/2007	ET
713	193	6/21/2007	ET

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	6/21/2007	ET
INVENTOR SEARCH - PALM / eDAN / EAST	6/21/2007	ET
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTION	6/21/2007	ET
NPL - IEEE XPLORE	6/21/2007	ET